
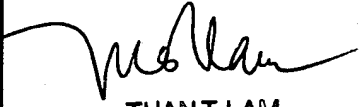
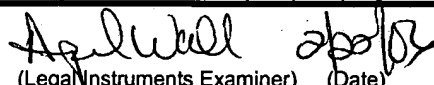


<b>Issue Classification</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/717,284	TAFT ET AL.	
	Examiner	Art Unit	
	Hiep Nguyen	2816	

ISSUE CLASSIFICATION									
ORIGINAL				CROSS REFERENCE(S)					
CLASS		SUBCLASS		CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
327		390		327	391				
INTERNATIONAL CLASSIFICATION				326	113				
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HIEP NGUYEN 02.01.06 (Assistant Examiner) (Date)		 <b>TUAN T. LAM</b> PRIMARY EXAMINER 2/4/06 (Primary Examiner) (Date)	Total Claims Allowed: 19	
 (Legal Instruments Examiner) (Date)			O.G. Print Claim(s) 1	O.G. Print Fig. 8

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant				<input type="checkbox"/> CPA				<input type="checkbox"/> T.D.				<input type="checkbox"/> R.1.47			
Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original		
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